

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10652327	ELZUR ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Hoang, Hieu T	2452	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	229, 230, 250	9/12/2007	HH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	9/12/2007	HH
NPL (Google, IETF, IEEE)	9/12/2007	HH
NPL (Google)	4/23/2008	HH
Updated EAST	4/24/2008	HH
Updated EAST	9/24/2008	HH
Updated EAST	2/11/2009	HH
Updated EAST	8/10/2009	HH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>